

INTERNATIONAL STANDARD

IEC
60770-2

Second edition
2003-01

Transmitters for use in industrial-process control systems –

Part 2: Methods for inspection and routine testing

*Transmetteurs utilisés dans les systèmes de conduite
des processus industriels –*

*Partie 2:
Méthodes pour l'inspection et les essais individuels de série*

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Reference number
IEC 60770-2:2003(E)

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Commission Electrotechnique Internationale
International Electrotechnical Commission
Международная Электротехническая Комиссия

PRICE CODE

M

For price, see current catalogue

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**TRANSMITTERS FOR USE IN INDUSTRIAL-PROCESS
CONTROL SYSTEMS –**
Part 2: Methods for inspection and routine testing

FOREWORD

- 1) The IEC (International Electrotechnical Commission) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of the IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, the IEC publishes International Standards. Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. The IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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International Standard IEC 60770-2 has been prepared by subcommittee 65B: Devices, of IEC technical committee 65: Industrial-process measurement and control.

This second edition cancels and replaces the first edition published in 1989 and constitutes a technical revision.

The text of this standard is based on the following documents:

FDIS	Report on voting
65B/468/FDIS	65B/477/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A bilingual edition may be issued at a later date.

The committee has decided that the contents of this publication will remain unchanged until 2008. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

INTRODUCTION

The methods of inspection and routine testing specified in this standard are intended for use in acceptance tests or after repair to verify the fulfilment of the performance specifications as established by the user. The methods given in this standard are primarily intended for the testing of conventional analogue transmitters. For setting up test procedures for microprocessor-based instruments IEC 62098 should be consulted.

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